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Field-ion microscopy (FIM)t has now entered its third decade. It .. this device a very useful supplement to any
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MULLER, Advances in Electronics and Electron Physics, 13, 83 (1960). 2. **A computer-controlled time-of-flight
atom-probe field-ion microscope** Atom-probe tomography (APT) is in the midst of a dynamic renaissance as a result
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Series (1996 - present), Trans. Muller E W 1960 Advances in Electronic and Electron Physics vol 13 (New York:
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